Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/767,763	OGAWA, HIDEHIKO	
Examiner	Art Unit	
Thomas D. Lee	2625	

	SEARCHED				
Class	Subclass	Date	Examiner		
358	1.15, 402, 440	2/22/2007	TDL		
379	100.01	2/22/2007	TDL		
379	100.08	2/22/2007	TDL		
379	100.13	2/22/2007	TDL		
379	100.17	2/22/2007	TDL		
updated		7/19/2007	TDL		
updated		10/10/2007	TDL		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
1	ce Search tout	10/10/2007	TDL	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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